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RADIO TEST REPORT

Test Report No.: 30IE0279-HO-01-A

Applicant : Sony Computer Entertainment Inc.

Type of Equipment : Reference Tool for PLAYSTATION®3

Model No. : DECR-1400A

FCC ID : AK8DECR1400A

Test regulation : FCC Part 15 Subpart C 2010

Section 15.207, Section 15.247 Class II Permissive Change

Test Result : Complied

1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.

2. The results in this report apply only to the sample tested.

3. This sample tested is in compliance with the above regulation.

4. The test results in this report are traceable to the national or international standards.

5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.

Date of test:

May 11 to 19, 2010

Representative test engineer:

Takumi Shimada Engineer of EMC Service

Approved by:

Mitsuru Fujimura Manager of EMC Service



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation. *As for the range of Accreditation in NVLAP, you may refer to the WEB address,

http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap

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SECTION 1: Customer information

Company Name	Sony Computer Entertainment Inc.
Brand Name	SONY
Address	2-6-21 Minamiaoyama, Minato-ku, Tokyo, 107-0062, Japan
Telephone Number	+81-3-6438-8023
Facsimile Number	+81-3-6438-8642
Contact Person	Akiko Tsukada

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment	Reference Tool for PLAYSTATION®3
Model No	DECR-1400A
Serial No	0201985: Used for Antenna Terminal Conducted tests
	0201984: Used for Conducted emission test and Radiated spurious
	emission test
Rating	AC 100-240V, 50/60Hz
Country of Mass-production	JAPAN
Receipt Date of Sample	April 29, 2010
Condition of EUT	Production model
	(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT	No modification by the test lab.

2.2 Product description

Model: DECR-1400A, referred to as the EUT in this report, is a Reference Tool for PLAYSTATION®3 to make software for game.

It contains Bluetooth (Ver. 2.0+EDR) module and IEEE802.11b/g WLAN module. Those modules do not transmit simultaneously.

Bluetooth (Ver. 2.0+EDR)

Equipment Type	Transceiver		
Frequency of Operation	2402-2480MHz		
Type of Modulation	FHSS (GFSK, π/4DQPSK, 8DP	SK)	
Bandwidth & Channel spacing	1MHz & 1MHz		
Power Supply (inner)	DC3.3V		
Antenna Type	Ant: 1: BT PIFA	Ant: 2: Dipole Antenna	
Antenna Connector Type	Ant: 1: N/A	Ant: 2: N/A	
Antenna Gain	Ant: 1: 2.57dBi max	Ant: 2: 1.90dBi max	

IEEE802.11b/g WLAN

EEEeovaniiong WEIII		
Equipment Type	Transceiver	
Frequency of Operation	2412-2462MHz	
Type of Modulation	DSSS/OFDM	
Bandwidth & Channel spacing	20MHz & 5MHz	
Power Supply (inner)	DC 3.3V/DC1.3V	
Antenna Type	Ant: 0: WLAN PIFA	Ant: 1: WLAN PIFA
Antenna Connector Type	Ant: 0: U.FL	Ant: 1: N/A
Antenna Gain	Ant: 0: 2.03dBi max	Ant: 1: 2.83dBi max

For IEEE802.11b/g WLAN part, please see the test report number 30IE0279-HO-01-B.

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part15 Subpart C: 2010, final revised on January 22, 2010 and effective

March 1, 2010

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators

Section 15.207 Conducted limits

Section 15.247 Operation within the bands 902-928MHz,

2400-2483.5MHz, and 5725-5850MHz

* The EUT complies with FCC Part 15 Subpart B: 2009, final revised on January 22, 2010 and effective March 1, 2010

3.2 Procedures and results

Item	Test Procedure	Specification	Worst Margin	Results	Remarks
Conducted Emission	FCC: ANSI C63.4:2003 7. AC powerline conducted emission measurements IC: RSS-Gen 7.2.2	FCC: Section 15.207 IC: RSS-Gen 7.2.2	QP 13.6dB, 0.60788, 0.60743MHz, N AV 8.3dB, 0.60743MHz, N	Complied	-
Carrier Frequency Separation	FCC: FCC Public Notice DA 00-705	FCC: Section15.247(a)(1) IC: RSS-210 A8.1 (b)		Complied	Conducted
20dB Bandwidth	FCC: FCC Public Notice DA 00-705	FCC: Section15.247(a)(1) IC: RSS-210 A8.1 (a)		N/A	Conducted
Number of Hopping Frequency	FCC: FCC Public Notice DA 00-705	FCC: Section15.247(a)(1)(iii) IC: RSS-210 A8.1 (d)	See data.	Complied	Conducted
Dwell time	FCC: FCC Public Notice DA 00-705	FCC: Section15.247(a)(1)(iii) IC: RSS-210 A8.1 (d)		Complied	Conducted
Maximum Peak Output Power	FCC: FCC Public Notice DA 00-705 IC: RSS-Gen 4.8	FCC: Section15.247(b)(1) IC: RSS-210 A8.4 (2)		Complied	Conducted
Spurious Emission & Band Edge Compliance	RSS-Gen 4.10	FCC: Section15.247(d) IC: RSS-210 A8.5	[Tx] 3.8dB 76.832MHz, QP, Hori [Rx] 4.5dB 76.842MHz, QP, Hori.	Complied	Conducted/ Radiated

st In case any questions arise about test procedure, ANSI C63.4: 2003 is also referred.

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FCC 15.31 (e)

This EUT provides stable voltage(DC 3.3V/DC1.3V) constantly to RF Module regardless of input voltage. Therefore, this EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

3.3 Addition to standard

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99% Occupied	IC: RSS-Gen 4.6.1	IC: RSS-Gen 4.6.1	N/A	N/A	Conducted
Bandwidth					

Other than above, no addition, exclusion nor deviation has been made from the standard.

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3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room	Conducted emission
(semi-	(<u>+</u> dB)
anechoic	150kHz-30MHz
chamber)	
No.1	2.6dB
No.2	2.9dB
No.3	3.3dB
No.4	2.8dB

Test room (semi- anechoic chamber)	Radiated emission (10m*)(<u>+</u> dB)			
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	
No.1	2.7dB	4.8dB	5.0dB	
No.2	-	-	-	
No.3	-	-	-	
No.4	-	-	-	

^{*10}m = Measurement distance

Test room (semi- anechoic	Radiated emission						
chamber)	(3m*)(<u>+</u> dB)				(1m*)	(<u>+</u> dB)	(0.5m*)(<u>+</u> dB)
	9kHz	30MHz	300MHz	1GHz	10GHz	18GHz	26.5GHz
	-30MHz	-300MHz	-1GHz	-10GHz	-18GHz	-26.5GHz	-40GHz
No.1	2.9dB	4.8dB	5.0dB	3.9dB	4.3dB	4.5dB	4.3dB
No.2	3.5dB	4.8dB	5.1dB	4.0dB	4.2dB	4.4dB	4.2dB
No.3	3.8dB	4.6dB	4.7dB	4.0dB	4.2dB	4.5dB	4.2dB
No.4	3.5dB	4.4dB	4.9dB	4.0dB	4.2dB	4.6dB	4.2dB

^{*3}m/1m/0.5m = Measurement distance

Power meter (<u>+</u> dB)				
Below 1GHz	Above 1GHz			
1.0dB	1.0dB			

Antenna terminal conducted emission			Antenna terminal	Channel power			
and	Power density (±dB)		and Power density (<u>+</u> dB) (<u>+</u> dB)		(<u>+</u> dB)		(<u>+</u> dB)
Below 1GHz	1GHz-3GHz	3GHz-18GHz	18GHz-26.5GHz	26.5GHz-40GHz			
1.0dB	1.1dB	2.7dB	3.2dB	3.3dB	1.5dB		

Conducted Emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test

Transmitter Spurious Emission: The data listed in this report meets the limits unless the uncertainty is taken into consideration. Receiver Spurious Emission: The data listed in this test report has enough margin, more than the site margin.

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3.5 **Test Location**

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Facsimile: +81 596 24 8124 Telephone: +81 596 24 8116

	FCC	IC Registration	Width x Depth x	Size of	Other
	Registration Number	Number	Height (m)	reference ground plane (m) / horizontal conducting plane	rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

^{*} Size of vertical conducting plane (for Conducted Emission test): 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Data of EMI, and Test instruments

Refer to APPENDIX.

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SECTION 4: Operation of E.U.T. during testing

4.1 **Operating Mode(s)**

Bluetooth (BT): Transmitting (Tx), Payload: PRBS9

Receiving (Rx)

Inquiry

Details of Operating Mode(s)

Test Item	Mode	Tested frequency	Tested Antenna
Conducted Emission	Tx (Hopping off) DH5, 3DH5	2402MHz	Ant: 1
Spurious Emission		2441MHz	Ant: 2
(Radiated)		2480MHz	
	Rx	2441MHz	Ant: 1
			Ant: 2
Spurious Emission	Tx (Hopping off) DH5, 3DH5	2402MHz	Ant: 1
(Conducted)		2441MHz	
		2480MHz	
	Rx	2441MHz	Ant: 1
Carrier Frequency Separation	Tx (Hopping on) DH5, 3DH5	2402MHz	Ant: 1
		2441MHz	
		2480MHz	
	Inquiry	2441MHz	Ant: 2
20dB Bandwidth	Tx (Hopping off) DH5, 3DH5	2402MHz	Ant: 1
		2441MHz	
		2480MHz	
	Inquiry	2441MHz	Ant: 2
Number of Hopping Frequency	Tx (Hopping on) DH5, 3DH5	-	Ant: 1
D 11.2	Inquiry	-	Ant: 2
Dwell time	Tx (Hopping on),	-	Ant: 1
	-DH1, DH3, DH5		
	-3DH1, 3DH3, 3DH5		
	Inquiry	-	Ant: 2
Maximum Peak Output Power	Tx (Hopping off) DH5, 3DH5	2402MHz	Ant: 1
•		2441MHz	Ant: 2
		2480MHz	
	Inquiry	2441MHz	Ant: 2
Band Edge Compliance	Tx DH5, 3DH5	2402MHz	Ant: 1
(Conducted)	-Hopping on	2480MHz	
	-Hopping off		
Band Edge Compliance	Tx DH5, 3DH5	2402MHz	Ant: 1
(Radiated)	-Hopping on	2480MHz	Ant: 2
	-Hopping off		
99% Occupied Bandwidth	Tx DH5, 3DH5	2402MHz	Ant: 1
•	-Hopping on	2441MHz	
	-Hopping off	2480MHz	

^{*}As a result of preliminary test, the formal test was performed with the above modes, which had the maximum payload length (except Dwell time test)

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^{*}As a result of preliminary check of output power with two antennas (Ant: 1 and Ant: 2), antenna terminal conducted test was performed with Ant: 1, which had the maximum peak output power. However, Ant: 2 was used for Inquiry test since Inquiry is only transmitted from Ant: 2 only.

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4.2 Configuration and peripherals

This page has been submitted for a separate exhibit.

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SECTION 5: Conducted Emission

Test Procedure and conditions

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane.

The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT, including peripherals aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from a Line Impedance Stabilization Network (LISN)/ Artificial mains Network (AMN) and excess AC cable was bundled in center.

For the tests on EUT with other peripherals (as a whole system)

I/O cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. All unused 50ohm connectors of the LISN(AMN) were resistivity terminated in 50ohm when not connected to the measuring equipment.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT in a Semi Anechoic Chamber.

The EUT was connected to a LISN (AMN).

An overview sweep with peak detection has been performed.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Detector : OP and AV : 0.15-30MHz Measurement range : APPENDIX Test data Test result

: Pass

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SECTION 6: Radiated Spurious Emission

Test Procedure

EUT was placed on a urethane platform of nominal size, 1.5m by 1.0m, raised 0.8m above the conducting ground plane.

The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane.

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The measurements were made with the following detector function of the test receiver and the Spectrum analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

Test Antennas are used as below;

Frequency	Below 30MHz	30MHz to 300MHz	300MHz to 1GHz	Above 1GHz
Antenna Type	Loop	Biconical	Logperiodic	Horn

In any 100kHz bandwidth outside the restricted band in which the spread spectrum intentional radiator is operating, the radio frequency power that is produced by the intentional radiator confirmed 20dB below that in the 100kHz bandwidth within the band that contains the highest level of the desired power, based on a radiated measurement.

20dBc was applied to the frequency over the limit of FCC 15.209 / Table 2 of RSS-210 2.7 (IC) and outside the restricted band of FCC 15.205 / Table 1 of RSS-210 2.7 (IC).

Frequency	Below 1GHz	Above 1GHz		
Instrument used	Test Receiver / Spectrum Analyzer	Spectrum Analyzer *1)		
Detector	QP	PK	AV	
IF Bandwidth	BW 120kHz(T/R)	RBW: 1MHz	RBW: 1MHz	
		VBW: 3MHz	VBW: 10Hz	
			or	
			RBW: 1MHz	
			VBW: 270Hz *2)	
	20dBc : RBW: 100kHz	20dBc: RBW:100kHz/VBW:300kHz		
	VBW: 300kHz (S/A)			
Test Distance	3m	3m (below 10GHz),		
		1m*2) (above 10GHz),		

^{*1)} The Spectrum Analyzer was used in 3dB resolution bandwidth.

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Measurement range : 30M-25GHz
Test data : APPENDIX
Test result : Pass

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^{*2)} Used for the band edge of the carrier and the harmonics that can be measured. The VBW is based on the inverse of the duty cycle (see Appendix).

^{*3)} Distance Factor: $20 \times \log (3.0 \text{m}/1.0 \text{m}) = 9.5 \text{dB}$

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SECTION 7: Antenna Terminal Conducted Tests

Test Procedure

The tests were made with below setting connected to the antenna port.

Test	Span	RBW	VBW	Sweep time	Detector	Trace	Instrument used
20dB Bandwidth	3MHz	30kHz	100kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth	Enough width to display 20dB Bandwidth	1 to 3% of Span	Three times of RBW	Auto	Peak	Max Hold	Spectrum Analyzer
Maximum Peak Output Power	-	-	-	Auto	Peak	-	Power Meter (Sensor: 50MHz BW)
Carrier Frequency Separation	3MHz or 5MHz	100kHz	300kHz	Auto	Peak	Max Hold	Spectrum Analyzer
Number of Hopping Frequency	30MHz	300kHz	1MHz	Auto	Peak	Max Hold	Spectrum Analyzer
Dwell Time	Zero Span	1MHz	3MHz	As necessary capture the entire dwell time per hopping channel	Peak	Max Hold	Spectrum Analyzer
Conducted Spurious Emission	Less or equal to 5GHz (Range: 30MHz-25GHz)	100kHz	300kHz	Auto	Peak	Max Hold	Spectrum Analyzer

The test results and limit are rounded off to two decimals place, so some differences might be observed.

Test data : APPENDIX Test result : Pass

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